



Title of Change:	AR0144CS Outgoing Defect Specification Mono Update.			
Effective date:	15 August 2018			
Contact information:	Contact your local ON Semiconductor Sales Office or < sonya.yip@onsemi.com >			
Type of notification:	This Product Bulletin is for notification purposes only. ON Semiconductor will proceed with implementation of this change upon publication of this Product Bulletin.			
Change Category:	<input type="checkbox"/> Wafer Fab	<input type="checkbox"/> Assembly Change	<input type="checkbox"/> Test Change	<input checked="" type="checkbox"/> Other Documentation
Change Sub-Category(s):	<input type="checkbox"/> Manufacturing Site Addition <input type="checkbox"/> Material Change <input checked="" type="checkbox"/> Datasheet/Product Doc change <input type="checkbox"/> Manufacturing Site Transfer <input type="checkbox"/> Product specific change <input type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Manufacturing Process Change <input type="checkbox"/> Other: _____			
Sites Affected:	ON Semiconductor Sites: None	External Foundry/Subcon Sites: None		
Description and Purpose:				
AR0144CS Outgoing Defect Specification was updated to correct an error. These changes do not affect form, fit, or function of the product.				
AR0144CS Outgoing Defect Specification Changes				
<p>1. In Conditions for Image Test B, changed "Sensor analog gain is 1.77x, digital gain is 1x" to "Sensor analog gain is 1.7x, digital gain is 1x"</p> <p><u>Old Section:</u></p> <p><i>Conditions for Image Test B</i> The following test conditions are used for "Definition 3: Very Bright Pixel Defect", "Definition 4: Bright Pixel Defect", "Definition 5: Very Dark Pixel Defect", and "Definition 6: Dark Pixel Defect":</p> <ul style="list-style-type: none"> • Full resolution images (four frames) are captured using a 1 ms integration time with a midlevel scene illumination such that sensor output is about 2800 LSBs. Frames are averaged for analysis • Sensor analog gain is 1.77x, digital gain is 1x <p><u>New Section:</u></p> <p><i>Conditions for Image Test B</i> The following test conditions are used for "Definition 3: Very Bright Pixel Defect", "Definition 4: Bright Pixel Defect", "Definition 5: Very Dark Pixel Defect", and "Definition 6: Dark Pixel Defect":</p> <ul style="list-style-type: none"> • Full resolution images (four frames) are captured using a 1 ms integration time with a midlevel scene illumination such that sensor output is about 2800 LSBs. Frames are averaged for analysis • Sensor analog gain is 1.7x, digital gain is 1x 				



Product Bulletin

Document # : PB22414X

Issue Date: 15 August 2018

List of Affected Parts:

AR0144CSSCO0SUKA0-CPBR
AR0144CSSCO0SUKA0-CRBR
AR0144CSSM00SUKA0-CPBR
AR0144CSSM00SUKA0-CRBR
AR0144CSSC20SUKA0-CPBR
AR0144CSSC20SUKA0-CRBR
AR0144CSSM20SUKA0-CPBR
AR0144CSSM20SUKA0-CRBR
AR0144CSSCO0SUD20
AR0144CSSC20SUD20
AR0144CSSM00SUD20
AR0144CSSM20SUD20
AR0144CSSM28SUD20